

Notice of References Cited

Application/Control No.

Applicant(s)/Patent Under Reexamination IKEDA, HIROSHI

Examiner

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,505,254 B1 1	01-2003	Johnson et al.	709/239
	В	US-2001/0052015	12-2001	LIN et al.	709/226
	С	US-2003/0052916 A1 :	03-2003	Stern, Joseph L.	345/760
	D	US-2003/0204756 A1 /	10-2003	Ransom et al.	713/300
	Ε	US-2002/0133573 A1 1	09-2002	MATSUDA et al.	709/220
·	F	US-			
	G	US-		`	
	Н	US-			
	_	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	2000550769	04-1999	Japan	Oki, E; Yamanaka, N	G06F013/00
	0	2001402660	05-2001	Japan	Fujitsu Ltd[FUIT]	T01
	Р	EP1-022875A1 →	01-2000	Japan	Yamanaka, Naoaki	H04L12/18
	Q					
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

	NON-PATENT DOCUMENTS							
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
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	х							

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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